


<b>Search Notes</b> 	<b>Application/Control No.</b> 10536589	<b>Applicant(s)/Patent Under Reexamination</b> TANAKA ET AL.
	<b>Examiner</b> William P Fletcher III	<b>Art Unit</b> 1792

SEARCHED			
Class	Subclass	Date	Examiner
427	407.1, 271, 335, 355, 377	6/1/2010	/WPF/

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor name search: no dbl pat rej required. EAST: strategy attached.	2/4/2008	/WPF/
EAST	6/1/2010	/WPF/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
427	407.1, 271, 335, 355, 377	6/1/2010	/WPF/

	/William Philip Fletcher III/ Primary Examiner, Art Unit 1715
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